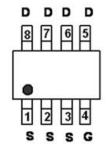
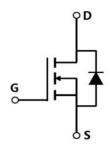


### **Main Product Characteristics:**

V <sub>DSS</sub>	30V				
R <sub>DS</sub> (on)	6.5mΩ (typ.)				
I <sub>D</sub>	15A ①				







SOP-8

**Pin Assignments** 

Schematic Diagram

### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



## **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

# **Absolute Max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current ①	15	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current ①	10	Α
I <sub>DM</sub>	Pulsed Drain Current ②	60	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ③	3	W
V <sub>DS</sub>	Drain-Source Voltage	30	V
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
Eas	Single Pulse Avalanche Energy @ L=0.5mH	63	mJ
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C



## **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
Reja	Junction-to-ambient (t $\leq$ 10s) $\oplus$	_	41	°C/W

## **Electrical Characterizes** @T<sub>A</sub>=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	_	6.5	8	mΩ	V <sub>GS</sub> =10V,I <sub>D</sub> = 15A
		_	9.8	14	mΩ	V <sub>GS</sub> =4.5V,I <sub>D</sub> =10A
V <sub>GS(th)</sub>	Gate threshold voltage	1	_	2.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	$V_{DS} = 30V, V_{GS} = 0V$
	0.1.1.0	_	_	100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	-100		V <sub>GS</sub> = -20V
Qg	Total gate charge	_	23	_		I <sub>D</sub> = 15A,
Q <sub>gs</sub>	Gate-to-Source charge	_	5	_	nC	V <sub>DS</sub> =15V,
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	_	6	_		V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-on delay time	_	9.6	_		
tr	Rise time	_	16.5	_	ns	V <sub>GS</sub> =10V, V <sub>DS</sub> =22V,
t <sub>d(off)</sub>	Turn-Off delay time	_	25.8	_		R <sub>GEN</sub> =2.2Ω,I <sub>D</sub> =10A
t <sub>f</sub>	Fall time	_	2.8	_		
C <sub>iss</sub>	Input capacitance	_	1172	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	122	_	pF	V <sub>DS</sub> = 30V
C <sub>rss</sub>	Reverse transfer capacitance	_	106	_		f = 1MHz

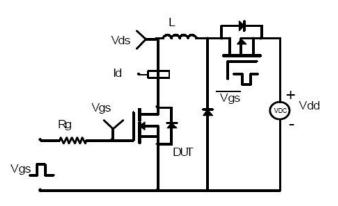
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	15	А	MOSFET symbol
	(Body Diode) ①					showing the
I <sub>SM</sub>	Pulsed Source Current	_	_	60	А	integral reverse
	(Body Diode) ①					p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	_	1.2	V	I <sub>S</sub> =15A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	10	_	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> =20A,
Qrr	Reverse Recovery Charge	_	3	_	nC	di/dt = 100A/μs

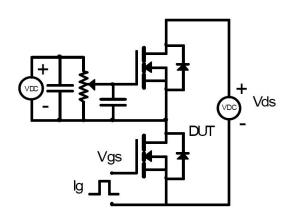


### **Test Circuits and Waveforms**

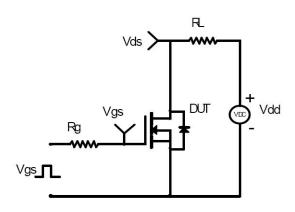
#### **EAS Test Circuit:**



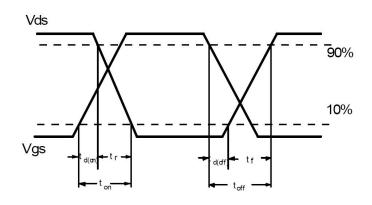
#### Gate charge test circuit:



#### **Switching Time Test Circuit:**



#### **Switching Waveforms:**

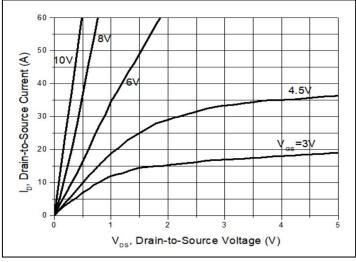


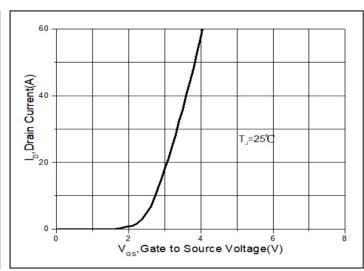
### Notes:

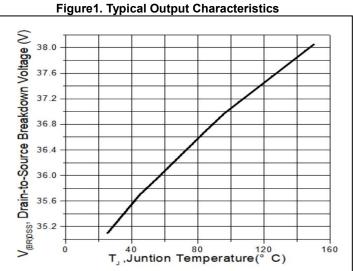
- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- $\ \ \,$  The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C



# **Typical Electrical and Thermal Characteristics**







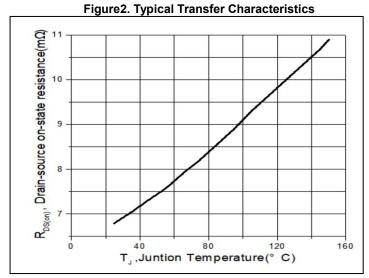
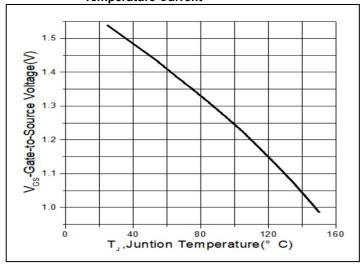


Figure 3. Drain-to-Source Breakdown Voltage vs. Junction
Temperature Current

Figure 4. Normalized On-Resistance vs. Junction Temperature



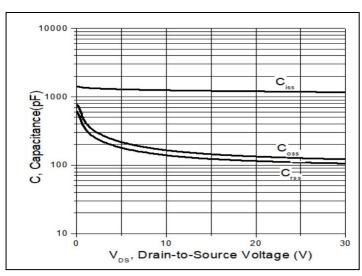


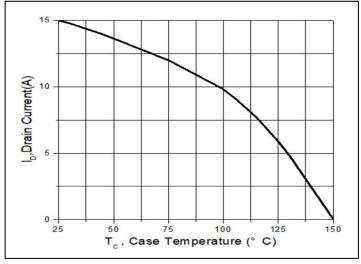
Figure 5. Normalized V<sub>GS</sub>(th) vs. Junction Temperature

Figure 6. Capacitance Characteristics





# **Typical Electrical and Thermal Characteristics**



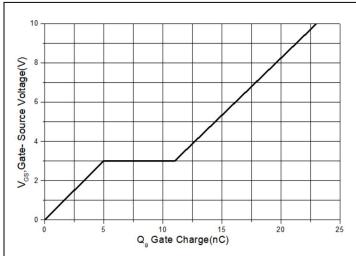


Figure 7. Drain Current vs. Junction Temperature

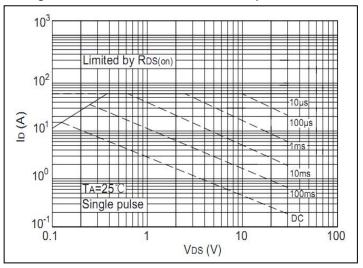


Figure 9. Safe Operation Area

Figure8. Gate Charge

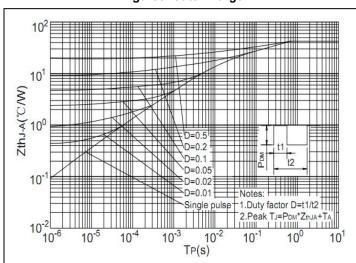
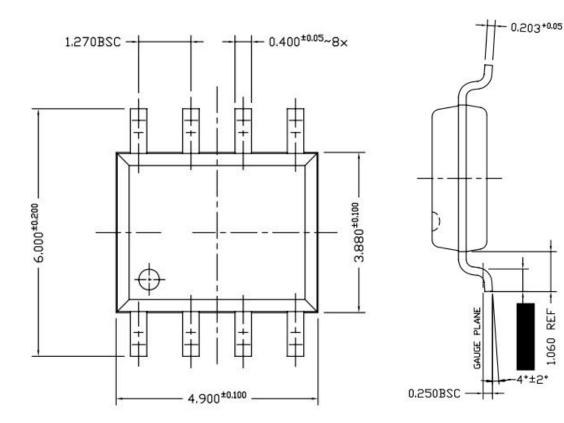


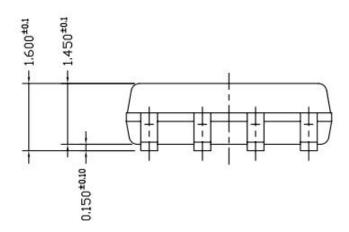
Figure 10. Transient Thermal Impedance



## **Mechanical Data:**

## SOP-8 Package Outline (Unit:mm)









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